

# Complementary MOSFET

ELM14609AA-N

## General Description

ELM14609AA-N uses advanced trench technology to provide excellent  $R_{ds(on)}$  and low gate charge.

## Features

- N-channel
- P-channel
- $V_{ds}=30V$
- $V_{ds}=-30V$
- $I_d=8.5A(V_{gs}=10V)$
- $I_d=-3A(V_{gs}=-10V)$
- $R_{ds(on)} < 18m\Omega (V_{gs}=10V)$
- $R_{ds(on)} < 130m\Omega (V_{gs}=-10V)$
- $R_{ds(on)} < 28m\Omega (V_{gs}=4.5V)$
- $R_{ds(on)} < 180m\Omega (V_{gs}=-4.5V)$
- $R_{ds(on)}$
- $R_{ds(on)} < 260m\Omega (V_{gs}=-2.5V)$

## Maximum Absolute Ratings

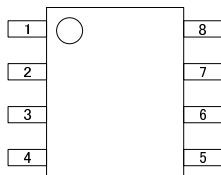
Parameter		Symbol	N-ch (Max.)	P-ch (Max.)	Unit	Note
Drain-source voltage		$V_{ds}$	30	-30	V	
Gate-source voltage		$V_{gs}$	$\pm 20$	$\pm 12$	V	
Continuous drain current	$T_a=25^\circ C$	$I_d$	8.5	-3.0	A	1
	$T_a=70^\circ C$		6.6	-2.4		
Pulsed drain current		$I_{dm}$	40	-6	A	2
Power dissipation	$T_a=25^\circ C$	$P_d$	2.00	2.00	W	
	$T_a=70^\circ C$		1.28	1.28		
Junction and storage temperature range		$T_j, T_{stg}$	-55 to 150	-55 to 150	$^\circ C$	

## Thermal Characteristics

Parameter		Symbol	Device	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$t \leq 10s$	$R\theta_{ja}$	N-ch	48.0	62.5	$^\circ C/W$	1
	Steady-state			74.0	110.0	$^\circ C/W$	
Maximum junction-to-lead	Steady-state	$R\theta_{jl}$		35.0	40.0	$^\circ C/W$	3
Maximum junction-to-ambient	$t \leq 10s$	$R\theta_{ja}$		P-ch	56.0	62.5	$^\circ C/W$
	Steady-state		81.0		110.0	$^\circ C/W$	
Maximum junction-to-lead	Steady-state	$R\theta_{jl}$	40.0		48.0	$^\circ C/W$	3

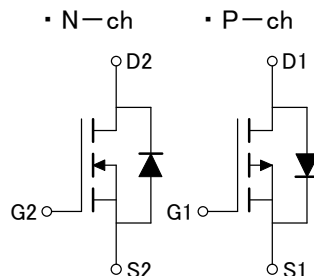
## Pin Configuration

SOP-8 (TOP VIEW)



Pin No.	Pin name
1	SOURCE2
2	GATE2
3	SOURCE1
4	GATE1
5	DRAIN1
6	DRAIN1
7	DRAIN2
8	DRAIN2

## Circuit



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## Electrical Characteristics (N-ch)

T<sub>a</sub>=25°C

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
<b>STATIC PARAMETERS</b>						
Drain-source breakdown voltage	BV <sub>dss</sub>	I <sub>d</sub> =250 μA, V <sub>gs</sub> =0V	30			V
Zero gate voltage drain current	I <sub>dss</sub>	V <sub>ds</sub> =24V V <sub>gs</sub> =0V			1	μA
		T <sub>j</sub> =55°C			5	
Gate-body leakage current	I <sub>gss</sub>	V <sub>ds</sub> =0V, V <sub>gs</sub> =±20V			100	nA
Gate threshold voltage	V <sub>gs(th)</sub>	V <sub>ds</sub> =V <sub>gs</sub> , I <sub>d</sub> =250 μA	1.0	1.8	3.0	V
On state drain current	I <sub>d(on)</sub>	V <sub>gs</sub> =10V, V <sub>ds</sub> =5V	40			A
Static drain-source on-resistance	R <sub>ds(on)</sub>	V <sub>gs</sub> =10V I <sub>d</sub> =8.5A		15.5	18.0	mΩ
		T <sub>j</sub> =125°C		22.3	27.0	
		V <sub>gs</sub> =4.5V, I <sub>d</sub> =6A		23.0	28.0	
Forward transconductance	G <sub>fs</sub>	V <sub>ds</sub> =5V, I <sub>d</sub> =8.5A		23		S
Diode forward voltage	V <sub>sd</sub>	I <sub>s</sub> =1A, V <sub>gs</sub> =0V		0.75	1.00	V
Max.body-diode continuous current	I <sub>s</sub>				3	A
<b>DYNAMIC PARAMETERS</b>						
Input capacitance	C <sub>iss</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =15V, f=1MHz		1040	1250	pF
Output capacitance	C <sub>oss</sub>			180		pF
Reverse transfer capacitance	C <sub>rss</sub>			110		pF
Gate resistance	R <sub>g</sub>			0.70	0.85	Ω
<b>SWITCHING PARAMETERS</b>						
Total gate charge (10V)	Q <sub>g</sub>	V <sub>gs</sub> =10V, V <sub>ds</sub> =15V, I <sub>d</sub> =8.5A		19.20	23.00	nC
Total gate charge (4.5V)	Q <sub>g</sub>			9.36	11.20	nC
Gate-source charge	Q <sub>gs</sub>			2.60		nC
Gate-drain charge	Q <sub>gd</sub>			4.20		nC
Turn-on delay time	t <sub>d(on)</sub>			5.2	7.5	ns
Turn-on rise time	t <sub>r</sub>	V <sub>gs</sub> =10V, V <sub>ds</sub> =15V		4.4	6.5	ns
Turn-off delay time	t <sub>d(off)</sub>	R <sub>l</sub> =1.8 Ω, R <sub>gen</sub> =3 Ω		17.3	25.0	ns
Turn-off fall time	t <sub>f</sub>			3.3	5.0	ns
Body-diode reverse recovery time	t <sub>rr</sub>	I <sub>f</sub> =8.5A, dI/dt=100A/μs		16.7	21.0	ns
Body-diode reverse recovery charge	Q <sub>rr</sub>	I <sub>f</sub> =8.5A, dI/dt=100A/μs		6.7	10.0	nC

### NOTE :

1. The value of R<sub>θja</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board of 2oz. Copper, in still air environment with T<sub>a</sub>=25°C. The value in any given applications depends on the user's specific board design, The current rating is based on the t<sub>≤10s</sub> thermal resistance rating.
2. Repetitive rating, pulse width limited by junction temperature.
3. The R<sub>θja</sub> is the sum of the thermal impedance from junction to lead R<sub>θjl</sub> and lead to ambient.
4. The static characteristics in Figures 1 to 6 are obtained using 80 μs pulses, duty cycle 0.5%max.
5. These tests are performed with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>a</sub>=25°C. The SOA curve provides a single pulse rating.

# Complementary MOSFET

## ELM14609AA-N

### ■ Typical Electrical and Thermal Characteristics (N-ch)

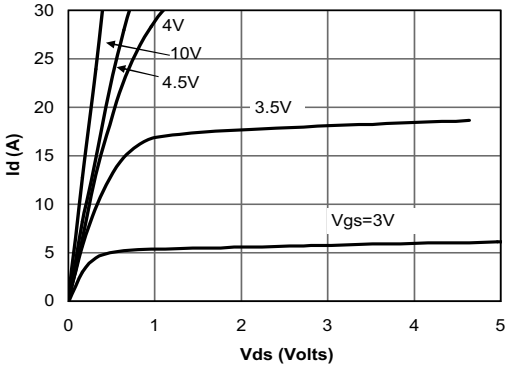


Fig 1: On-Region Characteristics

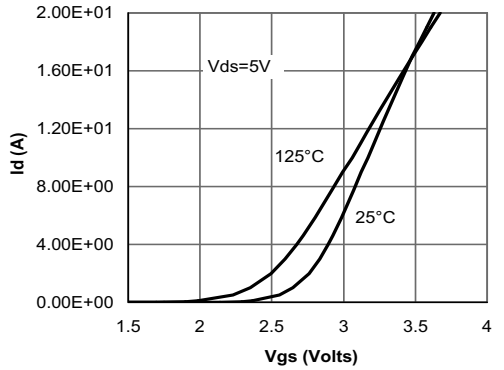


Figure 2: Transfer Characteristics

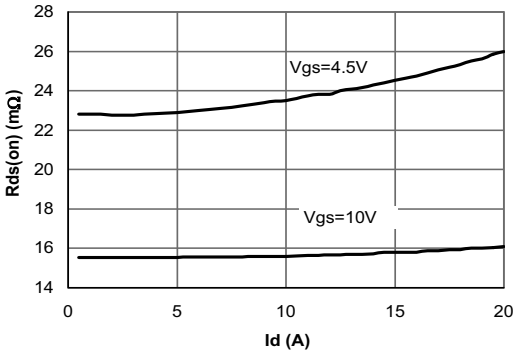


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

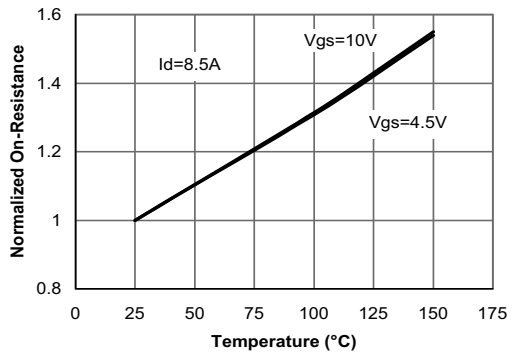


Figure 4: On-Resistance vs. Junction Temperature

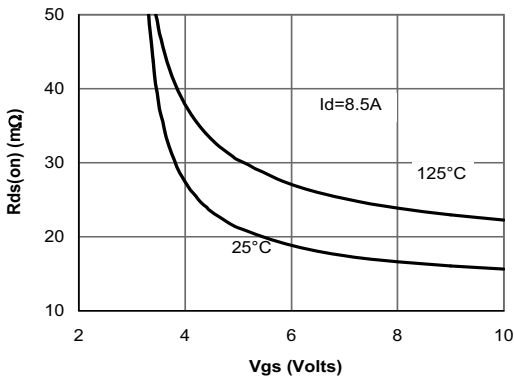


Figure 5: On-Resistance vs. Gate-Source Voltage

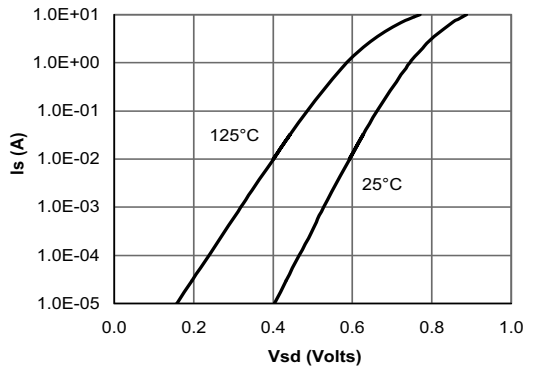


Figure 6: Body-Diode Characteristics

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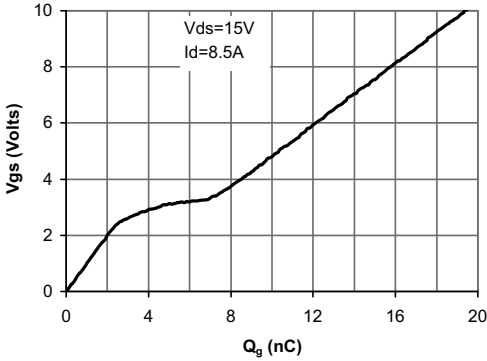


Figure 7: Gate-Charge Characteristics

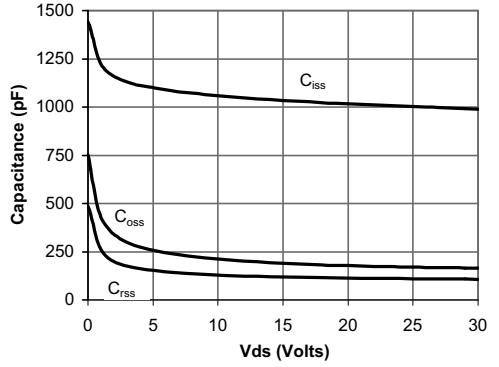


Figure 8: Capacitance Characteristics

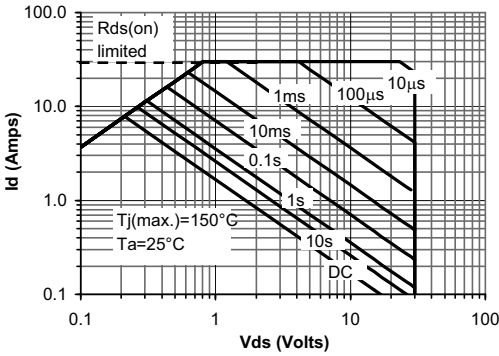


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

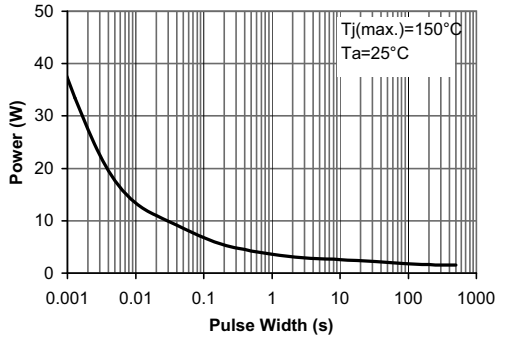


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

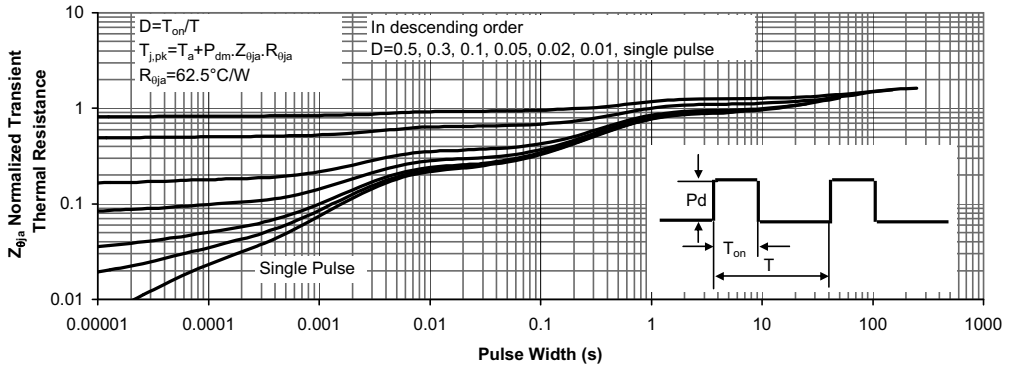


Figure 11: Normalized Maximum Transient Thermal Impedance

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### Electrical Characteristics (P-ch)

T<sub>a</sub>=25°C

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
<b>STATIC PARAMETERS</b>						
Drain-source breakdown voltage	BV <sub>dss</sub>	I <sub>d</sub> =-250 μA, V <sub>gs</sub> =0V	-30			V
Zero gate voltage drain current	I <sub>dss</sub>	V <sub>ds</sub> =-24V			-1	μA
		V <sub>gs</sub> =0V			-5	
		T <sub>j</sub> =55°C				
Gate-body leakage current	I <sub>gss</sub>	V <sub>ds</sub> =0V, V <sub>gs</sub> =±12V			±100	nA
Gate threshold voltage	V <sub>gs(th)</sub>	V <sub>ds</sub> =V <sub>gs</sub> , I <sub>d</sub> =-250 μA	-0.6	-1.0	-1.4	V
On state drain current	I <sub>d(on)</sub>	V <sub>gs</sub> =-4.5V, V <sub>ds</sub> =-5V	-10			A
Static drain-source on-resistance	R <sub>ds(on)</sub>	V <sub>gs</sub> =-10V		102	130	mΩ
		I <sub>d</sub> =-3A		154	200	
			T <sub>j</sub> =125°C			
		V <sub>gs</sub> =-4.5V, I <sub>d</sub> =-2A		128	180	mΩ
		V <sub>gs</sub> =-2.5V, I <sub>d</sub> =-1A		187	260	mΩ
Forward transconductance	G <sub>fs</sub>	V <sub>ds</sub> =-5V, I <sub>d</sub> =-3A	3.0	4.5		S
Diode forward voltage	V <sub>sd</sub>	I <sub>s</sub> =-1A, V <sub>gs</sub> =0V		-0.85	-1.00	V
Max. body-diode continuous current	I <sub>s</sub>				-2	A
<b>DYNAMIC PARAMETERS</b>						
Input capacitance	C <sub>iss</sub>			409		pF
Output capacitance	C <sub>oss</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =-15V, f=1MHz		55		pF
Reverse transfer capacitance	C <sub>rss</sub>			42		pF
Gate resistance	R <sub>g</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =0V, f=1MHz		12		Ω
<b>SWITCHING PARAMETERS</b>						
Total gate charge	Q <sub>g</sub>	V <sub>gs</sub> =-4.5V, V <sub>ds</sub> =-15V		4.40		nC
Gate-source charge	Q <sub>gs</sub>	I <sub>d</sub> =-3A		0.80		nC
Gate-drain charge	Q <sub>gd</sub>			1.32		nC
Turn-on delay time	t <sub>d(on)</sub>			5.3		ns
Turn-on rise time	t <sub>r</sub>	V <sub>gs</sub> =-10V, V <sub>ds</sub> =-15V		4.4		ns
Turn-off delay time	t <sub>d(off)</sub>	RI=5 Ω, R <sub>gen</sub> =3 Ω		31.5		ns
Turn-off fall time	t <sub>f</sub>			8.0		ns
Body diode reverse recovery time	t <sub>rr</sub>	I <sub>f</sub> =-3A, dI/dt=100A/μs		15.8		ns
Body diode reverse recovery charge	Q <sub>rr</sub>	I <sub>f</sub> =-3A, dI/dt=100A/μs		8.0		nC

#### NOTE :

1. The value of R<sub>θja</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board of 2oz. Copper, in still air environment with T<sub>a</sub>=25°C. The value in any given applications depends on the user's specific board design, The current rating is based on the t<sub>≤10s</sub> thermal resistance rating.
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### Typical Electrical and Thermal Characteristics (P-ch)

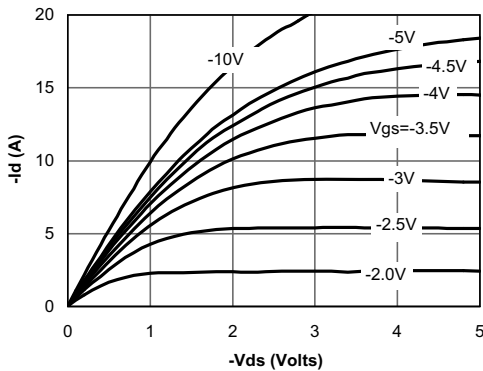


Fig 1: On-Region Characteristics

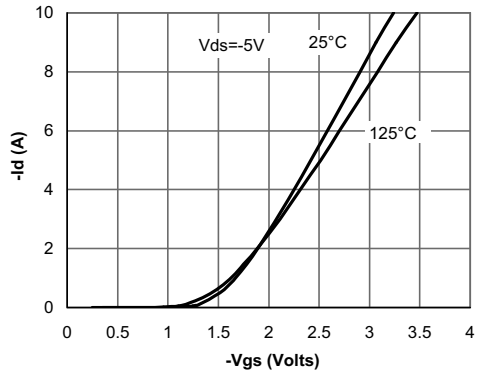


Figure 2: Transfer Characteristics

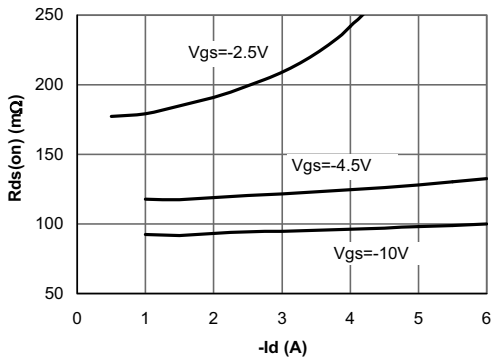


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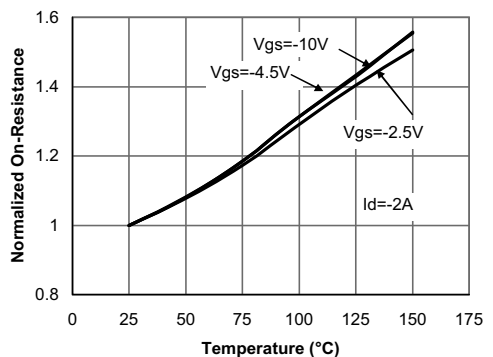


Figure 4: On-Resistance vs. Junction Temperature

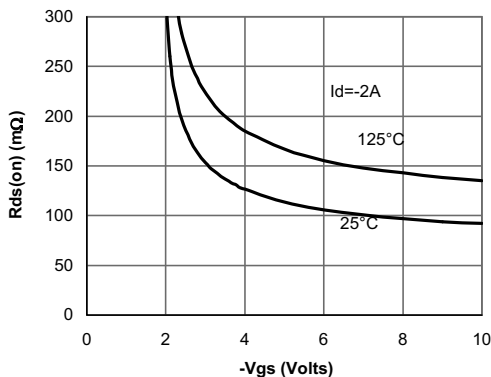


Figure 5: On-Resistance vs. Gate-Source Voltage

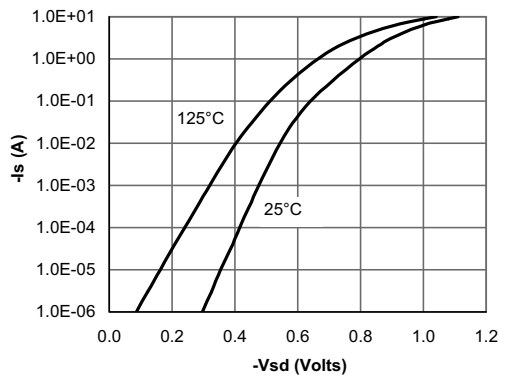


Figure 6: Body-Diode Characteristics

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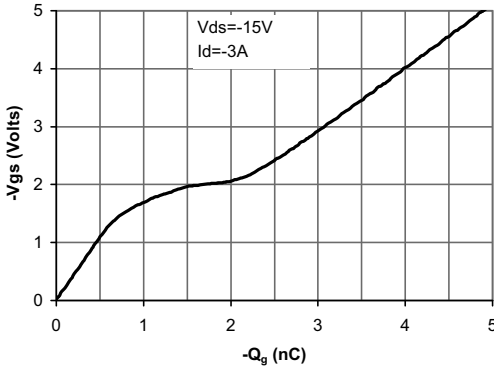


Figure 7: Gate-Charge Characteristics

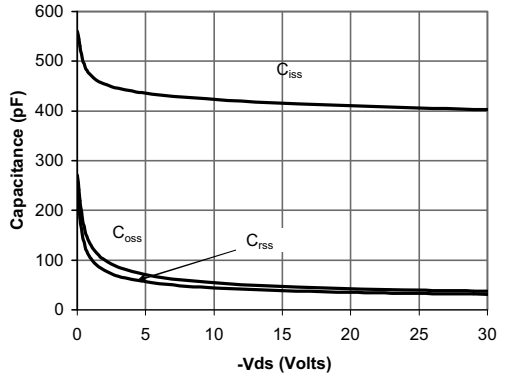


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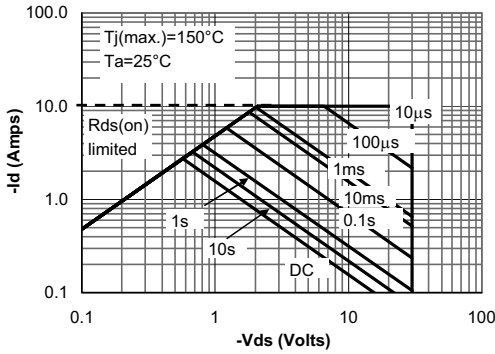


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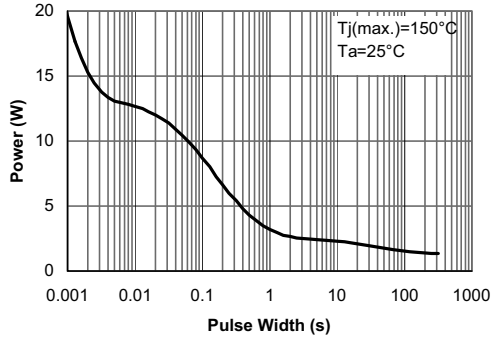


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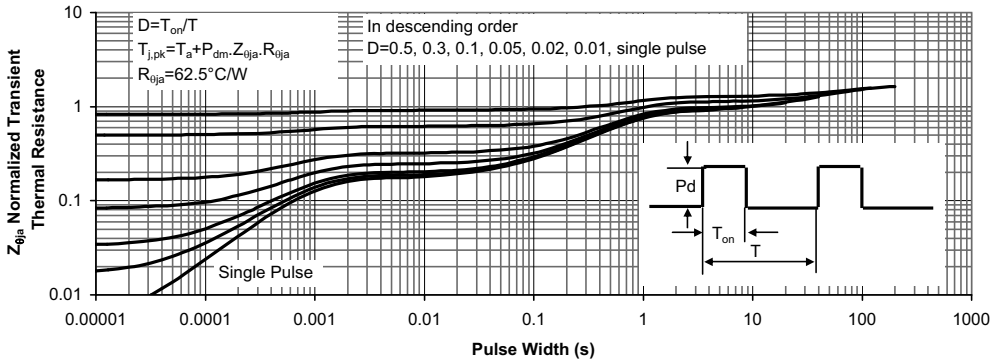


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